

Title (en)

METHOD FOR ADJUSTING AN ELECTRICAL PARAMETER ON AN INTEGRATED ELECTRONIC COMPONENT

Title (de)

VERFAHREN ZUR JUSTIERUNG EINES ELEKTRISCHEN PARAMETERS AUF EINER INTEGRIERTEN ELEKTRONISCHEN KOMPONENTE

Title (fr)

PROCEDE D'AJUSTAGE D'UN PARAMETRE ELECTRIQUE SUR UN COMPOSANT ELECTRONIQUE INTEGRE

Publication

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Application

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Abstract (en)

[origin: WO0169671A1] The invention concerns a method for making an integrated electronic component arranged on a substrate wafer comprising at least two metallising steps. The invention is characterised in that the value of an electrical parameter of the component is determined after a metallising step, and one of the following metallising processes is carried out with an adjusting mask selected among n predefined masks to obtain a desired value of the parameter, the selection of the adjusting mask being performed in accordance with the predetermined value of the electrical parameter.

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